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Substitute for form 1449A/B/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Compleat if Known

Application Number Unassigned 10/769,936
Filing Date February 2, 2004
First Named Inventor Vlasta BRUSIC
Group Art Unit Unassigned 1742
Examiner Name Unassigned
Attorney Docket Number 100172
LVM Reference Number 219817

Sheet 1 of 1

U.S. PATENT DOCUMENTS

Examiner Initials	Doc. No.	U.S. Patent Document		Name of Patentee or Applicant	Date of Publication	Filing Date If Appropriate
		Application or Patent Number	Kind Code			
NS	AA	5,217,586		Datta et al.	Jun. 8, 1993	
NS	AB	5,256,565		Bernhardt, et al.	Oct. 26, 1993	
NS	AC	5,575,706		Tsai, et al.	Nov. 19, 1996	
NS	AD	5,807,165		Uzoh, et al.	Sep. 15, 1998	
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NS	AN	6,478,936	B1	Volodarsky, et al.	Nov. 12, 2002	
NS	AO	2002/0098779		Tsai et al.	Jul. 25, 2002	
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FOREIGN PATENT DOCUMENTS

Examiner Initials	Doc. No.	Foreign Patent Document			Name of Patentee or Applicant	Date of Publication	Translation	
		Office	Application or Patent Number	Kind Code			Yes	No**

OTHER - NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Doc. No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number (s), publisher, city and/or country where published.	Translation	
			Yes	No**

Examiner Signature

/Nicholas Smith/

Date Considered

03/27/2007

* A concise statement of relevance is being submitted in lieu of a translation. 37 CFR 1.98(a)(3).

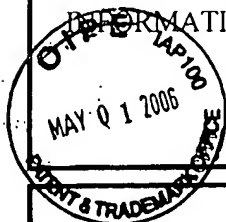
* An English-language equivalent/patent, or an English-language abstract, or an English-language version of the search report or action by a foreign patent office in a counterpart foreign application indicating the degree of relevance found by the foreign office is being submitted in lieu of a concise explanation of relevance under 37 CFR 1.98(a)(3).

Comparable to Form PTO/SB/08A

Complete if Known

Application Number:	10/769,936
Filing Date:	02-Feb-04
First Named Inventor::	Vlasta BRUSIC
Art Unit:	1742
Examiner Name:	Leader, W.
Atty. Docket No.:	100172

INFORMATION DISCLOSURE STATEMENT
BY APPLICANT



U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number Number-Kind Code (if known)	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages Or Figures Appear
NS	B1	3838032	24-Sep-1974	Yarnilski et al.	
NS	B2	4123335	31-Oct-1978	Seyl et al.	
NS	B3	5980708	09-Nov-1999	Champagne et al.	
NS	B4	2002/125141	12-Sep-2002	Wilson Gregory et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code- Number-Kind Code (if known)	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages Or Figures Appear	T

OTHER DOCUMENTS (NON PATENT LITERATURE DOCUMENTS)

Examiner Initials	Cite No.	Author's NAME, title of the article, book, magazine, journal, serial, symposium, catalog, etc., date, page(s), volume-issue number(s), publisher, city and/or country of publication	T
NS	B5	Svante Aberg, <i>Measurement of Uncompensated Resistance and Double Layer Capacitance During the Course of a Dynamic Measurement: Correction for IR Drop and Charging Currents in Arbitrary Voltammetric Techniques</i> , Journal of Electroanalytical Chemistry, vol. 419, pp. 99-103; 1996	
NS	B6	Yarnitzki, <i>Dynamic Compensation of the Overall and Uncompensated Cell Resistance in a Two- or Three- Electrode System-Transient Techniques</i> , Analytical Chemistry, vol. 47, no.6, pp. 880-884; 1975	
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Examiner's Signature: /Nicholas Smith/

Date Considered: 03/27/2007